



Laser Fault Injection in a 32-bit Microcontroller: from the Flash Interface to the Execution Pipeline

Vanthanh Khuat, Jean-Luc Danger, Jean-Max Dutertre September 2021

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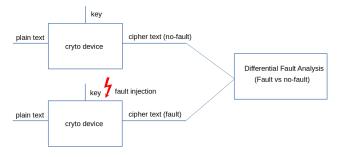
7. Comparison of different skip instruction fault models obtained with LFI

8. Conclusions & future works





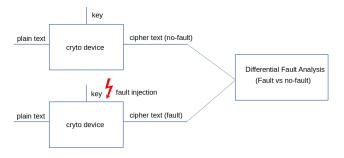
Fault injection







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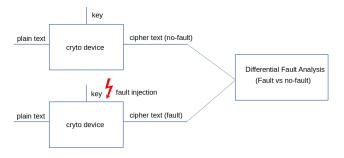


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Fault injection



- FI is an active side-channel attack in which the attacker induces stress to the target, forcing it to produce a fault result.
- The fault result is further used to extract secret information by differential fault analysis (fault vs no-fault).





¹barenghi2009low; balasch2011depth.

²riviere2015high; beckers2019characterization.

³skorobogatov2002optical; dutertre2019experimental.





Clock glitch or Voltage glitch¹

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- Electromagnetic fault injection²
- Laser fault injection (LFI)³
 - The laser has a very high spacial and temporal resolution because the pulse can be confined a very small space and lasts for a very short time.

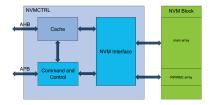
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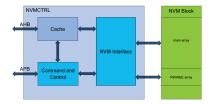




⁴SAMD21_datasheet_microchip.





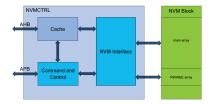


Our target is SAMD21G18A, with the following features:⁴

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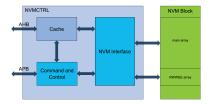


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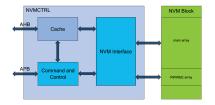
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- is a 32-bit MCU;
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- has an 8 lines 64 bits cache;

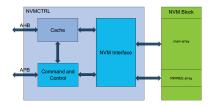




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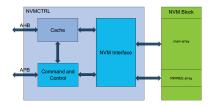
- is a 32-bit MCU;
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- investigating the impact of LFI parameters such as the PW and the power on the faults;
- comparing the instruction(s) skip fault models obtained with LFI at different positions.



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2. Experimental setup and methodology

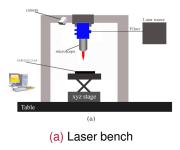
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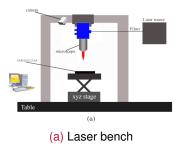
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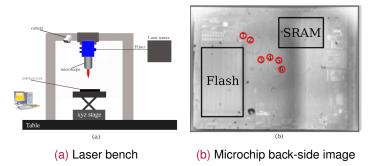
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Wavelength: 1064 nm, power: 0 - 3 W, PW: 5 ns - 1 s (more details can be found in⁵).

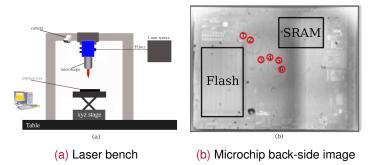
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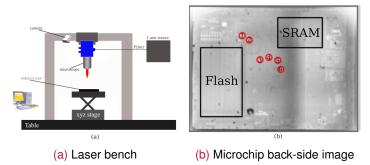
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The MCU was configured to work at 12 MHz, with zero waitstate. ⁵dutertre2019experimental.



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For each injection parameter, 100 tests are performed. At the beginning, a test without LFI was performed to make sure the program functions correctly and the data is used as the reference.



- i₅. add r1,r1,#0x01
- i₆. add r2,r2,#0x01
- i7. add r3,r3,#0x01
- i₈. add r4,r4,#0x01
- i₉. add r0,r0,#0x05
- i₁₀. add r0,r0,#0x06
- i_{11} . add r0,r0,#0x07
- i₁₂. add r0,r0,#0x08

(a) test code

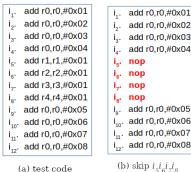


- add r0,r0,#0x01 i, add r0,r0,#0x02 i., add r0.r0.#0x03 i₃. add r0.r0.#0x04 i₄. add r1,r1,#0x01 i₅. add r2.r2,#0x01 i_e. add r3.r3.#0x01 i., add r4,r4,#0x01 İ., add r0,r0,#0x05 i., add r0.r0.#0x06 i,,,. add r0,r0,#0x07
- i₁₁. add r0,r0,#0x07 i₁₂. add r0,r0,#0x08

(a) test code



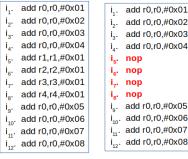




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(b) skip i₅i₆i₇i₈: instructions (i₅, i₆, i₇, i₈) are replaced by instructions equivalent to (nop, nop, nop, nop);





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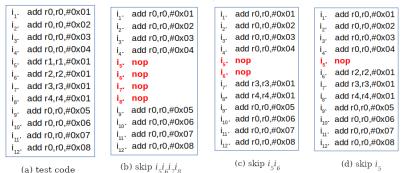
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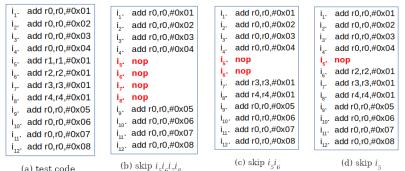
- (b) skip i₅i₆i₇i₈: instructions (i₅, i₆, i₇, i₈) are replaced by instructions equivalent to (nop, nop, nop, nop);
- (c) skip $i_5 i_6$: instructions (i_5 , i_6) are replaced by (*nop*, *nop*);





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- (c) skip $i_5 i_6$: instructions (i_5 , i_6) are replaced by (*nop*, *nop*);
- (d) skip i₅: instruction (i₅) is replaced by instruction (nop).

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add r0,r0,#0x01 i.,. add r0.r0.#0x02 i.,. add r0,r0,#0x03 i.,. add r0,r0,#0x04 i,. add r1.r1.#0x01 i., add r2,r2,#0x01 i., add r3.r3.#0x01 i... add r4,r4,#0x01 add r0,r0,#0x05 add r0.r0.#0x06 add r0,r0,#0x07 i.,. i₁₂. add r0,r0,#0x08

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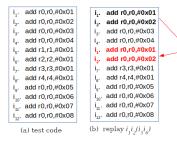


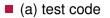
add r0,r0,#0x01 i.e. i2. add r0,r0,#0x02 add r0,r0,#0x03 i.,. add r0,r0,#0x04 i,. add r1.r1.#0x01 i., add r2,r2,#0x01 i., add r3.r3.#0x01 i... add r4,r4,#0x01 add r0,r0,#0x05 add r0.r0.#0x06 add r0,r0,#0x07 i.,. i,,, add r0,r0,#0x08

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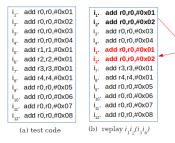






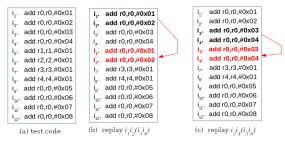






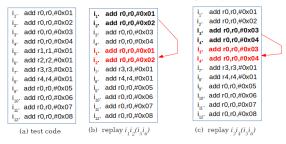
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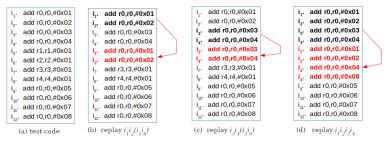




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- (b) replay i₁i₂(i₅i₆): instructions (i₅, i₆) are overwritten by instructions(i₁, i₂);
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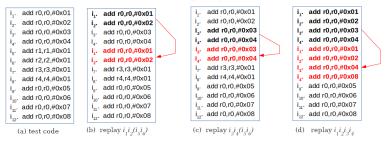




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- (d) replay *i*₁*i*₂*i*₃*i*₄: instructions (*i*₅, *i*₆, *i*₇, *i*₈) are overwritten by instructions (*i*₁, *i*₂, *i*₃, *i*₄).



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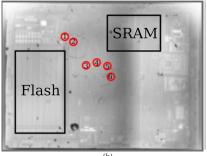


Faults at six positions

Laser power: 1.5 W, PW: 50 ns.



Faults at six positions



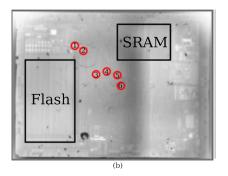
(b)

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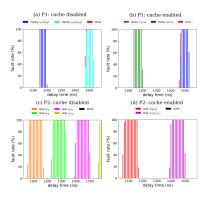
Faults at six positions



- Laser power: 1.5 W, PW: 50 ns.
- Six positions marked with red circular shapes with different fault behavior were found.



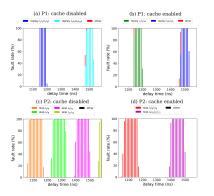
from The flash interface to the execution pipeline: P1 and P2



⁶vkhuat_emc_europe_2021; vkhuat_dsd_2021.



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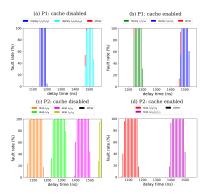
 The fault is related to block of two or four instructions depending on the cache operation mode;

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ΓΕΙ ΕΟΟ

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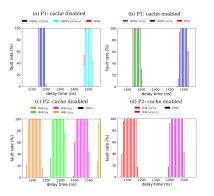
- The fault is related to block of two or four instructions depending on the cache operation mode;
- Two fault models: skip and replay of instruction block are observed;

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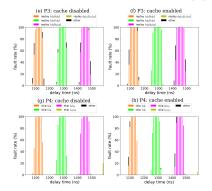
The fault behavior is the same with results obtained in⁶, in which we ascribed the fault to impact of EMFI and LFI to the Flash interface buffer.

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from The flash interface to the execution pipeline: P3 and P4

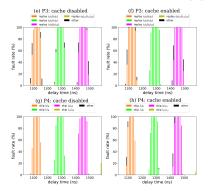


from The flash interface to the execution pipeline: P3 and P4





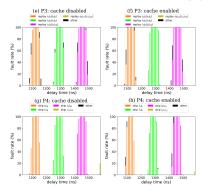
from The flash interface to the execution pipeline: P3 and P4



The fault is related to a block of two instructions for both cache operation modes;



from The flash interface to the execution pipeline: P3 and P4



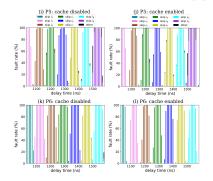
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from The flash interface to the execution pipeline: P5 and P6

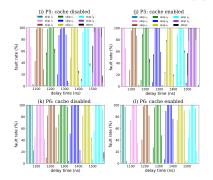


from The flash interface to the execution pipeline: P5 and P6





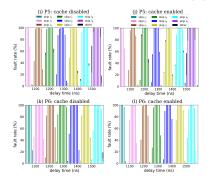
from The flash interface to the execution pipeline: P5 and P6



The fault is related to a single instruction;



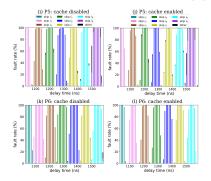
from The flash interface to the execution pipeline: P5 and P6



- The fault is related to a single instruction;
- Single instruction skip was obtained at position P5 and P6.



from The flash interface to the execution pipeline: P5 and P6



- The fault is related to a single instruction;
- Single instruction skip was obtained at position P5 and P6.
- There is a phase shift of one clock cycle between the fault at position 5 and 6.



	CLOCK	1	2	3	4
AHB access	HTRANS	NESQ	IDLE	NESQ	IDLE
	HADDR	a _s		a,	
	HRDATA		1. 1.		<i>i</i> ₇ <i>i</i> ₈
Core pipeline	Fetch	i,	i _s	i,	i,
	Execute	i,	i,	i _s	i _e

(a) Normal execution



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AHB access	HTRANS	NESQ	IDLE	NESQ	IDLE
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(a) Normal execution

(a) Normal execution process.



	CLOCK	1	2	3	4		
AHB access	HTRANS	NESQ	IDLE	NESQ	IDLE		
	HADDR	a _s		a,			
	HRDATA		1. 1.		$I_7 = I_8$		
Core pipeline	Fetch	i,	i _s	i _s	i,		
	Execute	i,	i,	i _s	i _c		
(a) Normal execution							
	CLOCK	1	2	3	4		
AHB access	HTRANS	NESQ	IDLE	NESQ	IDLE		
	HADDR	a _s		a,			
	HRDATA		1. 1.		$I_{\rm S} = I_{\rm S}$		
Core pipeline	Fetch	- I ₄	Ι,	i,	- 1 ₈		
	Execute	i,	i,	i,	i,		

(b) Laser-induced replay of two instructions

■ (a) Normal execution process.





(b) Laser-induced replay of two instructions

- (a) Normal execution process.
- (b) Laser-induced prevention of AHB bus update, resulting in replay of two instructions.





(c) Laser-induced modification of two instructions

- (a) Normal execution process.
- (b) Laser-induced prevention of AHB bus update, resulting in replay of two instructions.

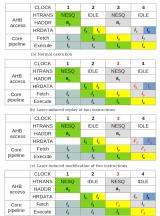




⁽c) Laser-induced modification of two instructions

- (a) Normal execution process.
- (b) Laser-induced prevention of AHB bus update, resulting in replay of two instructions.
- (c) Laser-induced instructions corruption of data loaded into ABH bus, resulting in skip of two instructions.



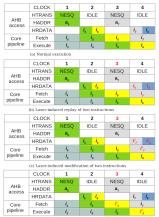


(d) Laser-induced fault on core pipeline fetch stage

- (a) Normal execution process.
- (b) Laser-induced prevention of AHB bus update, resulting in replay of two instructions.
- (c) Laser-induced instructions corruption of data loaded into ABH bus, resulting in skip of two instructions.



Fault mechanism hypothesis



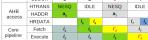
(d) Laser-induced fault on core pipeline fetch stage

- (a) Normal execution process.
- (b) Laser-induced prevention of AHB bus update, resulting in replay of two instructions.
- (c) Laser-induced instructions corruption of data loaded into ABH bus, resulting in skip of two instructions.
- (d) Laser-induced fault on pipeline fetch.



Fault mechanism hypothesis







⁽e) Laser-induced fault on core pipeline execution stage

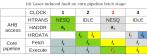
- (a) Normal execution process.
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- (d) Laser-induced fault on pipeline fetch.



Fault mechanism hypothesis



	(c) Laser-ind	uced modific	ation (of two	instructions		
	CLOCK	1	2		3	4	
AHB access	HTRANS	NESQ	IDLE		NESQ	IDLE	
	HADDR	a _s			a ₇		
	HRDATA		- İ ₅	i _s		i,	- İ ₈ -
Core pipeline	Fetch	1.	18		P_{θ}	I,	
	Execute	l ₃	- 14		1,	P	



⁽e) Laser-induced fault on core pipeline execution stage

- (a) Normal execution process.
- (b) Laser-induced prevention of AHB bus update, resulting in replay of two instructions.
- (c) Laser-induced instructions corruption of data loaded into ABH bus, resulting in skip of two instructions.
- (d) Laser-induced fault on pipeline fetch.
- (e) Laser-induced fault on the pipeline execution.



 Position P1: the replay of a block of instructions due to laser-induced prevention of the Flash interface buffer updating process;





- Position P1: the replay of a block of instructions due to laser-induced prevention of the Flash interface buffer updating process;
- Position P2: the modification of a block instructions (including skip) due to laser-induced bit corruption of instruction's opcodes in the Flash interface buffer;



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- Position P2: the modification of a block instructions (including skip) due to laser-induced bit corruption of instruction's opcodes in the Flash interface buffer;
- Position P3: the replay of two instructions due to laser-induced prevention of loading data into the AHB bus;



- Position P1: the replay of a block of instructions due to laser-induced prevention of the Flash interface buffer updating process;
- Position P2: the modification of a block instructions (including skip) due to laser-induced bit corruption of instruction's opcodes in the Flash interface buffer;
- Position P3: the replay of two instructions due to laser-induced prevention of loading data into the AHB bus;
- Position P4: the modification of two instructions (including skip) due to laser-induced bit(s) corruption of instructions loaded into the AHB bus;



- Position P1: the replay of a block of instructions due to laser-induced prevention of the Flash interface buffer updating process;
- Position P2: the modification of a block instructions (including skip) due to laser-induced bit corruption of instruction's opcodes in the Flash interface buffer;
- Position P3: the replay of two instructions due to laser-induced prevention of loading data into the AHB bus;
- Position P4: the modification of two instructions (including skip) due to laser-induced bit(s) corruption of instructions loaded into the AHB bus;
- Position P5: the modification of a single instruction (including skip) due to laser-induced fault in the core pipeline fetch stage;



- Position P1: the replay of a block of instructions due to laser-induced prevention of the Flash interface buffer updating process;
- Position P2: the modification of a block instructions (including skip) due to laser-induced bit corruption of instruction's opcodes in the Flash interface buffer;
- Position P3: the replay of two instructions due to laser-induced prevention of loading data into the AHB bus;
- Position P4: the modification of two instructions (including skip) due to laser-induced bit(s) corruption of instructions loaded into the AHB bus;
- Position P5: the modification of a single instruction (including skip) due to laser-induced fault in the core pipeline fetch stage;
- Position P6: the modification of a single instruction (including skip) due to laser-induced fault in the core pipeline execution stage.



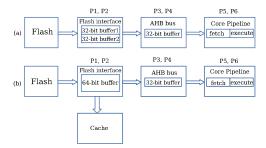






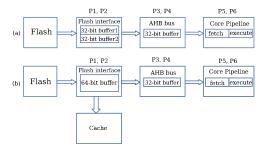
(a) cache disabled;





(a) cache disabled;

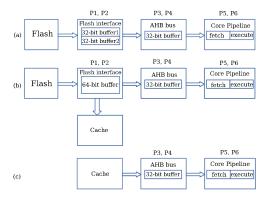




(a) cache disabled;

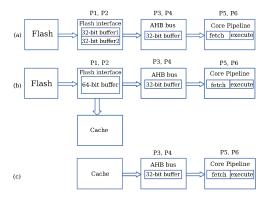
(b) cache enabled: cache miss;





- (a) cache disabled;
- (b) cache enabled: cache miss;





- (a) cache disabled;
- (b) cache enabled: cache miss;
- (c) cache enabled: cache hit.



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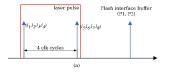
4. Impact of the pulse width

- 5. Impact of the laser power
- 6. Fault at bit level characterization

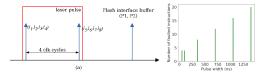
7. Comparison of different skip instruction fault models obtained with LFI

8. Conclusions & future works

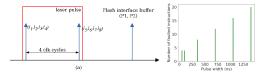










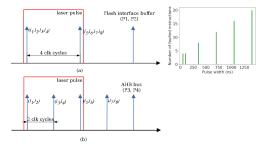


■ (a) Flash interface buffer: 20 faulted instructions.



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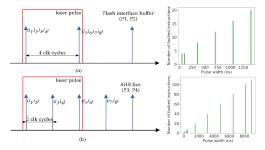




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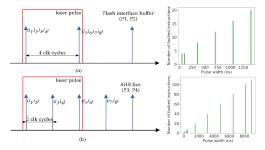






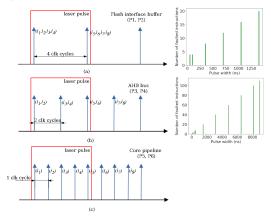
■ (a) Flash interface buffer: 20 faulted instructions.



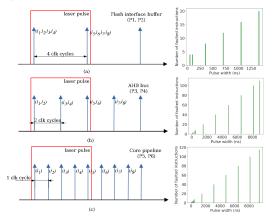


- (a) Flash interface buffer: 20 faulted instructions.
- (b) AHB bus: 110 faulted instructions

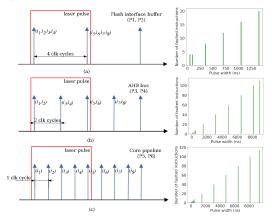




- (a) Flash interface buffer: 20 faulted instructions.
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- (a) Flash interface buffer: 20 faulted instructions.
- (b) AHB bus: 110 faulted instructions
- (c) Pipeline (fetch or execution): 115 faulted instructions



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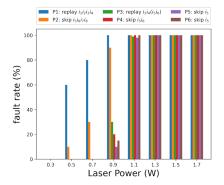
- 4. Impact of the pulse width
- 5. Impact of the laser power
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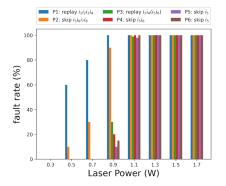


Impact of the laser power on the fault rates





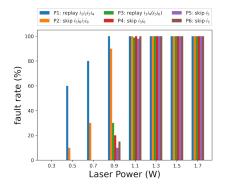
Impact of the laser power on the fault rates



The laser power has a direct impact on the fault rates; as the power increases the fault rates increase accordingly.



Impact of the laser power on the fault rates



- The laser power has a direct impact on the fault rates; as the power increases the fault rates increase accordingly.
- The Flash interface buffer seems to be more sensitive to the laser pulse as compared to the AHB bus and the core pipeline.



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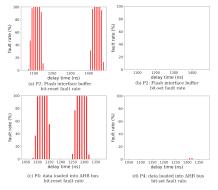
8. Conclusions & future works



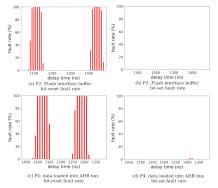
Isl r0,r0, #0x00 Isl r0,r0, #0x00 Isl r0,r0, #0x00 Isl r0,r0, #0x00 (a) bit-set detection sub r7,r7, #0xff sub r7,r7, #0xff sub r7,r7, #0xff sub r7,r7, #0xff(b) bit-reset detection

- The opcode of lsl r0,r0,#0x00 is 0x0000 (all bits' values are 0)
- The opcode of sub r7,r7,#0xff is 0x3fff (most of the bits'values are 1)



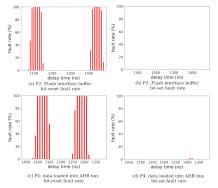






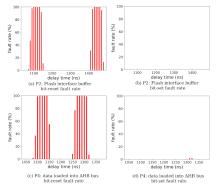
Many faults were detected when the buffers were filled with bits at 1.





- Many faults were detected when the buffers were filled with bits at 1.
- Almost no fault was detected when the buffers were filled with bits at 0.





- Many faults were detected when the buffers were filled with bits at 1.
- Almost no fault was detected when the buffers were filled with bits at 0.
- At bit level the faults are bit-reset rather than bit-set.

ΤΕΙ ΕΓΟΙ

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ldr r1, #address ldr r2, #address ldr r3, #address ldr r4, #address

.....

(a) test code





ldr r1, #address ldr r2, #address ldr r3, #address ldr r4, #address

.....

(a) test code

ldr r1, #address ldr r2, #address ldr r3, #address ldr r4, #address

.

(b) skip fault



ldr r1, #address ldr r2, #address ldr r3, #address ldr r4, #address

.

ldr r1, #address ldr r2, #address ldr r3, #address ldr r4, #address

.

(a) test code

(b) skip fault

"skip" fault models were obtained by faulting the Flash interface buffer, AHB bus, Pipeline: fetch, Pipeline: execution.



ldr r1, #address ldr r2, #address ldr r3, #address ldr r4, #address

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ldr r1, #address ldr r2, #address ldr r3, #address ldr r4, #address

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(a) test code

(b) skip fault

- "skip" fault models were obtained by faulting the Flash interface buffer, AHB bus, Pipeline: fetch, Pipeline: execution.
- The execution time of instruction Idr rx, #address is two clock cycles.



ldr r1, #address ldr r2, #address ldr r3, #address ldr r4, #address

.

ldr r1, #address ldr r2, #address ldr r3, #address ldr r4, #address

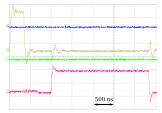
.

(a) test code

(b) skip fault

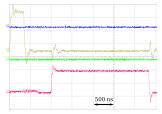
- "skip" fault models were obtained by faulting the Flash interface buffer, AHB bus, Pipeline: fetch, Pipeline: execution.
- The execution time of instruction Idr rx, #address is two clock cycles.
- The execution time of instruction **nop** is one clock cycles.





(a) No fault





(a) No fault

1 clock cycle = ~83.2 ns

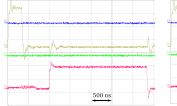
---- pulse command

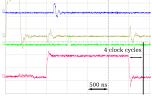
----- trigger

---- pulse image

test code execution window





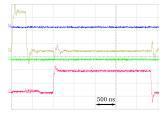


(a) No fault

(b) P2: Fault on the Flash interface buffer

- 1 clock cycle = ~83.2 ns
 - ---- pulse command
 - ----- trigger
 - ---- pulse image
 - test code execution window





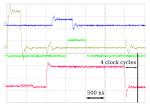
(a) No fault

- 1 clock cycle= ~83.2 ns
 - ---- pulse command
 - ---- trigger
 - ---- pulse image
 - test code execution window

(b) P2: Fault on the Flash interface buffer

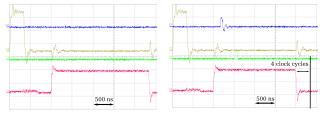
500 ns

4 clock cycles

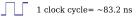


(c) P4: Fault on data loaded into the AHB bus



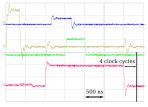


(a) No fault



- ---- pulse command
- ---- trigger
- ---- pulse image
- test code execution window

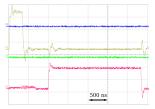
(b) P2: Fault on the Flash interface buffer



(c) P4: Fault on data loaded into the AHB bus

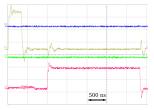
Flash interface buffer, AHB bus: Reduction in the length of code execution windows by 4 clocks cycles. -> *ldr* instructions were replaced by *nop* operations.





(a) No fault

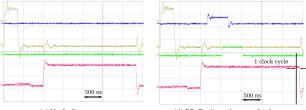




(a) No fault

- 1 clock cycle = ~83.2 ns
 - ---- pulse command
 - ----- trigger
 - ---- pulse image
 - test code execution window



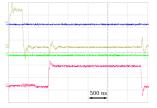


(a) No fault

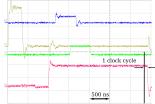
(d) P5: Fault on the core fetch

- 1 clock cycle = ~83.2 ns
 - ---- pulse command
 - ----- trigger
 - ---- pulse image
 - ----- test code execution window



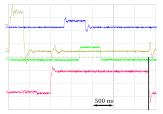


(a) No fault



(d) P5: Fault on the core fetch

- 1 clock cycle= \sim 83.2 ns
- ---- pulse command
- ---- trigger
- ---- pulse image
- test code execution window



(e) P6: Fault on the core execution





(e) P6: Fault on the core execution

Pipeline: No reduction in the length of code execution windows. -> *ldr* instructions were replaced by "unknown" operations.



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- The faults of pipeline fetch and execution are with a single instruction, and single instruction skip with fault rate of 100 % was obtained.







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V. Khuat, J. Danger, J. Dutertre



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- Tens to more than one hundred of instructions were faulted by increasing the laser PW.
- At bit level, the faults at Flash interface buffer and AHB bus were identified to to be bit-reset rather than bit-set.
- The skips fault obtained at different positions were compared by comparing the related signals such as the pulse duration, the execution windows.





Validation of the faults obtained in this work on other devices.



Thanks for your attention!



V. Khuat, J. Danger, J. Dutertre